

Application/Control No.	Applicant(s)/Patent un Reexamination	der
10/706,653	WAKUMOTO ET AL.	
Examiner	Art Unit	
Sved Zaidi	2616	•

SEARCHED				
Class	Subclass	Date	Examiner	
370	241	11/15/2007	sz	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH	_	)
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	11/15/2007	SZ
Inventor : Wakumoto et al	11/15/2007	SZ
IEEE Xplore Database(http://ieeexplore.ieee.org/Xp lore/DynWel.jsp)	11/15/2007	SZ
(370/241 370/248 370/395.31 370/216).CCLS.	11/15/2007	SZ
Consulted with SPE Kwang bin Yao.	11/15/2007	SZ